

A class of rank-based test for left-truncated and right-censored data

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Abstract A class of rank-based tests is proposed for the two-sample problem with left-truncated and right-censored data. The class contains as special cases the extension of log-rank test and Gehan test. The asymptotic distribution theory of the test is presented. The small-sample performance of the test is investigated under a variety of situations by means of Monte Carlo simulations.

Keywords Two-sample tests · Left-truncated and right-censored data